

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/753,257	CHAN ET AL.	
Examiner	Art Unit	
Matthew Heneghan	2134	

SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				
		-			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
L		<u></u>			

SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
EAST, keyword, citation searches. Researched using Menezes & Schneier	2/21/2006	МН
100		
· · · · · · · · · · · · · · · · ·		